



Metrology for Solid State Lighting

# Comparison of Efficacy Determination of SSL products

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> Metrology for SSL Workshop Teddington 24-25 April 2013

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- **Goal**: determination of the state-of-the-art of SSL characterization at NMIs through regular calibration services
- Primary set of parameters:
  - Total luminous flux
  - Electrical power
  - Luminous efficacy
- Secondary set of parameters:
  - Correlated Colour Temperature (CCT)
  - Chromaticity (x, y)



## Artefacts



Identifier	Picture	Manufacturer	Model	Nominal CCT	Rated voltage or current	Rated power
1	<b>V</b>	Philips	Master LED bulb E27	2700 K	230 V AC	12 W
2		Osram	PAR16 20 CW 20°	5000 K	230 V AC	5 W
3	1	RetroFix	SMD Clear Tube 120 cm length 6000K 140°	6000 K	230 V AC	18 W
4		Osram	64476 BT Sil 100W E27	3000 K	230 V AC	100 W

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## **Participants**



Laboratory	Instrument used for Iuminous flux	Instrument used for colorimetric quantities		
Aalto	Sphere photometer (1.65 m)	Sphere spectroradiometer		
CSIC	Sphere photometer (3 m)	Sphere spectroradiometer		
INRIM	Goniophotometer	Goniospectroradiometer (2.795 m)		
LNE	Sphere photometer (2 m)	Sphere spectroradiometer		
MKEH	Sphere photometer (1.5 m)	Sphere spectroradiometer		
NPL	Goniophotometer	Goniospectroradiometer (1.677 m)		
РТВ	Goniophotometer	Goniospectroradiometer (2. 5 m)		
SMU	Sphere photometer (1m)	Sphere spectroradiometer		
SP	Sphere photometer (1.5 and 3 m)	Sphere spectroradiometer		
VSL (pilot)	Sphere photometer (3 m)	Sphere spectroradiometer		

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## Instruments





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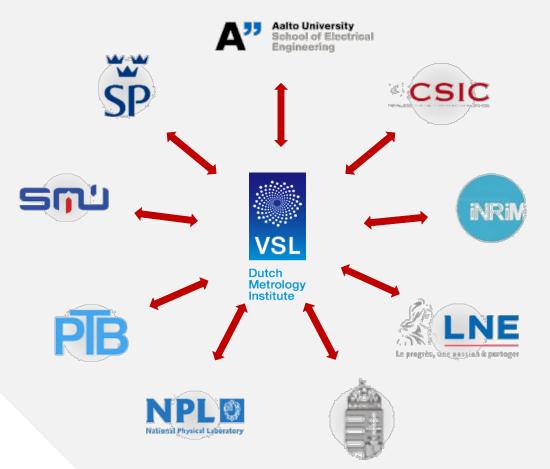
P 5

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## **Comparison scheme**





- 9 sets of artefacts
  - 1. Measured by pilot
  - 2. Measured by one participant lab
  - 3. Remeasured by pilot
  - Motivation:
    - Comparison duration
    - Stability of artefacts

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P 6

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## Measurement procedure

- 230 V 50 Hz power supply
  - Measurement of RMS current and RMS power during photometric measurement
- Ambient temperature (25 ± 1) °C
  - Measured at same height and within 1 m of lamp
  - Correction if measured at different temperature
- All lamps mounted base-up
  - Except TL
- Artefacts seasond by pilot for 100 h
- Stabilization to within 0.5% over 30 min window by participants
  - Light output and electrical power
- Measurement according to normal calibration procedure

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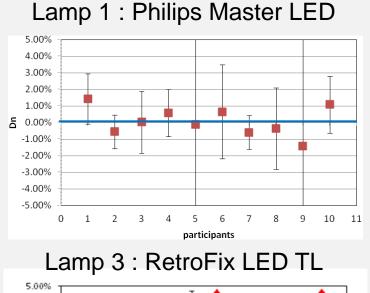
## Data analysis

- To compare results there should be a single reference value
- But different artefacts used
- Solution scale back to "virtual" artefact based on pilot lamp data
- Unilateral degree-of-equivalence Dn : relative difference of participant result to reference vale
- Uncertainty includes both uncertainty of participant and reference



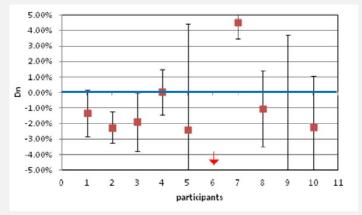
## **Results: luminous flux**



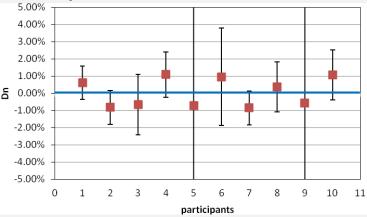


#### 4.00% 3.00% 2.00% 1.00% 5 0.00% -1.00% ·2.00% -3.00% -4.00% -5.00% 0 2 3 9 10 11 1 4 5 participants

#### Lamp 2 : Osram LED spot



## Lamp 4 : Osram incandescent



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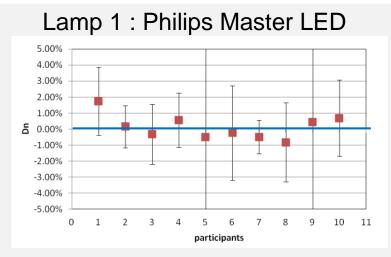
P 9

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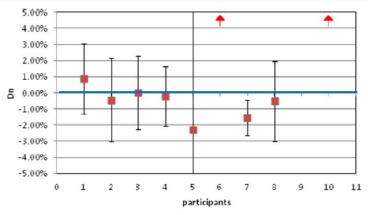


# Results: luminous efficacy



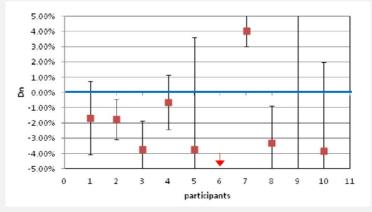


#### Lamp 3 : RetroFix LED TL

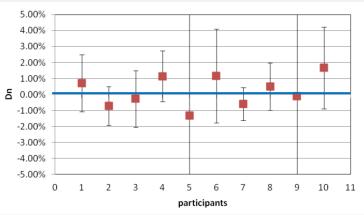


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#### Lamp 2 : Osram LED spot



#### Lamp 4 : Osram incandescent

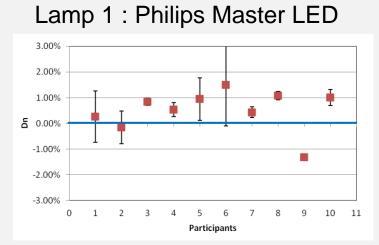


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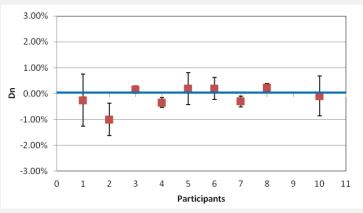


# Results: electrical power



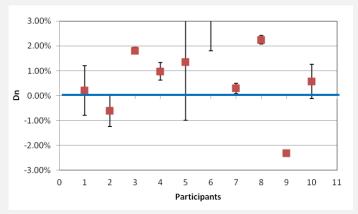


#### Lamp 3 : RetroFix LED TL

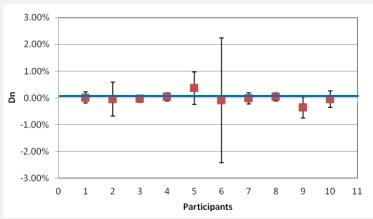


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#### Lamp 2 : Osram LED spot



## Lamp 4 : Osram incandescent

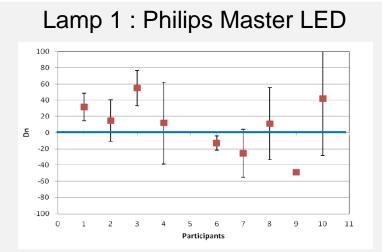


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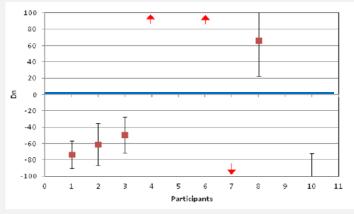


## **Results: CCT**

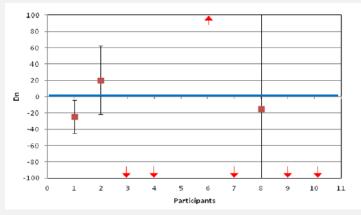




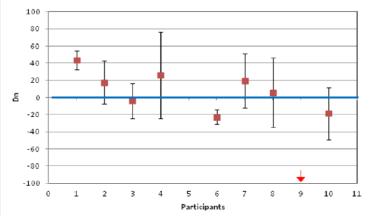
#### Lamp 3 : RetroFix LED TL



## Lamp 2 : Osram LED spot



#### Lamp 4 : Osram incandescent



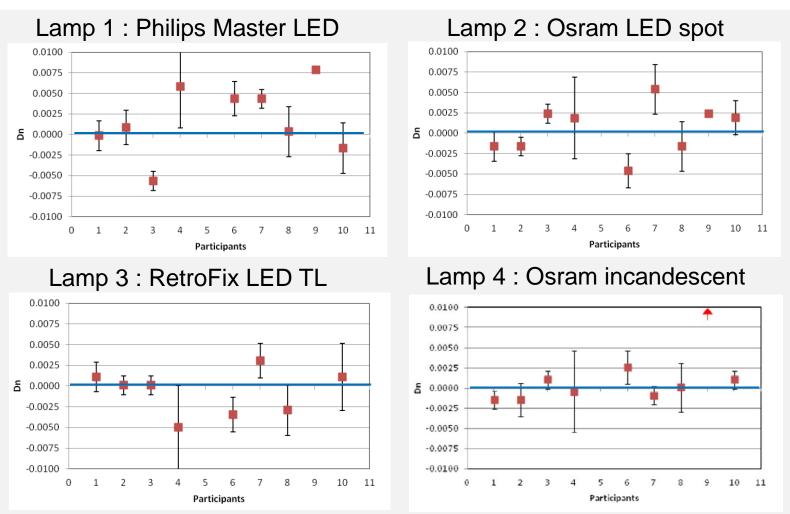
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## **Results: chromaticity x**





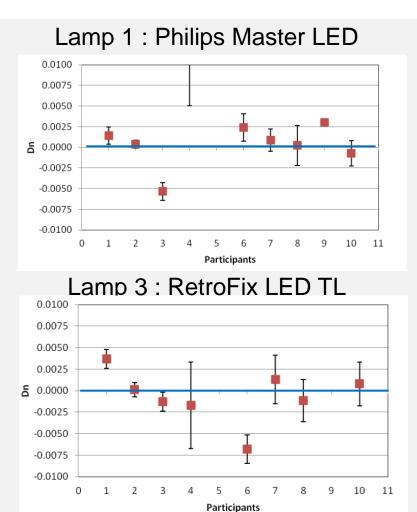
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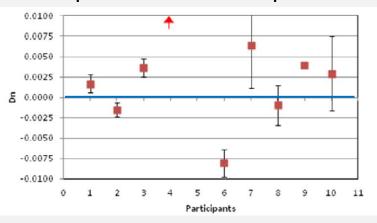


## **Results: chromaticity y**

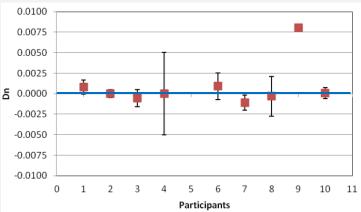




#### Lamp 2 : Osram LED spot



#### Lamp 4 : Osram incandescent



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P 15

## Conclusions



- Luminous flux and efficacy:
  - Good agreement for for Philips Master LED
  - Large deviations for LED spot
  - Two extreme outliers; otherwise good agreement for LED TL
- Electrical power: underestimated uncertainties for all three LED lamps
- Colorimetric measurements: large deviations
  - In particular for CCT
  - LED spot and LED TL most difficult
  - No general agreement for incandescent, but better than for LED lamps



## Recommendations

- Measurement procedures should be specified in more detail in order to obtain comparable results
- Alternatively, anything left open in the specification should be included in the uncertainty
- Extra effort should be put into quantifying the uncertainties for colorimetric parameters



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The research leading to these results has received funding from the European Union on the basis of Decision No 912/2009/EC.

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## Data scaling



- Participant *n* measures for their artefact of type *m*:
- Pilot measures for same artefact:
- Pilot overall value for artefact type *m*:

- Large difference between individual artefacts; factor:
- "Virtual" data for participant *n*:

$$X_{n,m}$$
  $n = 2, ..., 10; m = 1, ..., 4$ 

$$X_{n,m}^{P} = \frac{1}{2} \left( X_{n,m}^{P,\text{before}} + X_{n,m}^{P,\text{after}} \right)$$

$$X_{1,m} = \frac{1}{9} \sum_{n=2}^{10} X_{n,m}^{P}$$

$$f_{n,m} = \frac{X_{n,m}^{P}}{X_{1,m}}$$

$$\widetilde{X}_{n,m} = \frac{X_{n,m}}{f_{n,m}}; \quad \widetilde{X}_{1,m} = X_{1,m}$$

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**Reference value** 



-2 (**x**z

- Based on weighted-mean with cut-off, following CCPR guideline:

$$\begin{split} \widetilde{X}_{m}^{\text{RV}} &= \sum_{n=1}^{10} w_{n,m} \widetilde{X}_{n,m} \qquad w_{n,m} = \frac{u_{\text{adj}}(X_{n,m})}{\sum_{n=1}^{10} u_{\text{adj}}^{-2}(X_{n,m})} \\ u_{\text{adj}}(X_{n,m}) &= \begin{cases} u_{\text{rel}}(X_{n,m}) & \text{if } u_{\text{rel}}(X_{n,m}) \ge u_{\text{cut-off}} \\ u_{\text{cut-off}} & \text{if } u_{\text{rel}}(X_{n,m}) < u_{\text{cut-off}} \end{cases} \\ u_{\text{cut-off}} & \text{if } u_{\text{rel}}(X_{n,m}) < u_{\text{cut-off}} \end{cases} \end{split}$$

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P 19

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- Participant results are evaluated using the unilateral degree-of-equivalence:

$$D_{n,m} = \frac{\widetilde{X}_{n,m}}{\widetilde{X}_{m}^{\text{RV}}} - 1$$
$$u_{\text{rel}}(D_{n,m}) = \sqrt{u_{\text{rel}}^{2}(\widetilde{X}_{m}^{\text{RV}}) + u_{\text{rel}}^{2}(\widetilde{X}_{n,m})}$$

$$u_{\rm rel}(\tilde{X}_m^{\rm RV}) = \sqrt{\frac{1}{\sum_{n=1}^{10} u_{\rm adj}^{-2}(X_{n,m})}}$$

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## **Outlier summary**



	Lamp 1: Philips Master LED	Lamp 2: Osram LED spot	Lamp 3: RetroFix LED TL	Lamp 4: Osram incandescent
Luminous flux	-	4	3	-
Luminous efficacy	-	5	3	-
Electrical power	7	6	5	-
ССТ	4	7	8	3
Chromaticity x	5	5	3	3
Chromaticity y	5	7	3	2

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Metrology for SSL Workshop 24-25 April 2013 - Comparison P 21